

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/577,720	FUNAHASHI ET AL.
	Examiner	Art Unit
	Tan T. Nguyen	2827

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
365	49	5/1/2007	TNT
365	189.04	5/1/2007	TNT
365	189.07	5/1/2007	TNT
365/195		5/1/2007	TNT